

### Description

The DMNH6042SSDQ uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

### **General Features**

 $V_{DS} = 60V \ I_D = 6.5 \ A$   $R_{DS(ON)} < 36m\Omega @ V_{GS} = 10 \ V$  $R_{DS(ON)} < 48m\Omega @ V_{GS} = 4.5 \ V$ 

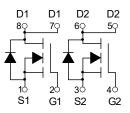
### Application

Battery protection Load switch

Uninterruptible power supply



SOP-8



#### **Dual N-Channel MOSFET**

#### Package Marking and Ordering Information

	<b>U</b>		
Product ID	Pack	Brand	Qty(PCS)
DMNH6042SSDQ	SOP-8	HXY MOSFET	3000

### Absolute Maximum Ratings@Tj=25°C(unless otherwise specified)

Symbol	Parameter	Rating	Units	
Vds	Drain-Source Voltage	60	V	
V <sub>GS</sub>	Gate-Source Voltage	<u>+</u> 20	V	
I <sub>D</sub> @T <sub>A</sub> =25℃	Drain Current, V <sub>GS</sub> @ 4.5V <sup>3</sup>	6.5	А	
I₀@T₄=70°C	Drain Current, V <sub>GS</sub> @ 4.5V <sup>3</sup>	5	A	
Ідм	Pulsed Drain Current <sup>1</sup>	30	A	
P <sub>D</sub> @T <sub>A</sub> =25℃	Total Power Dissipation	2.1	W	
Тѕтс	Storage Temperature Range	-55 to 150	°C	
TJ	Operating Junction Temperature Range	-55 to 150	°C	
Rthj-a	Maximum Thermal Resistance, Junction- ambient <sup>3</sup>	60	°C/W	



# DMNH6042SSDQ

Dual N-Channel Enhancement Mode MOSFET

### Electrical Characteristics (T<sub>A</sub>=25<sup>°</sup>Cunless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	V <sub>GS</sub> =0V I <sub>D</sub> =250µA 60		-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA
On Characteristics (Note 3)			•	•		
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	1.0	1.4	2.0	V
Durin Origina On Otata Davistana	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =6A		32	36	mΩ
Drain-Source On-State Resistance		V <sub>GS</sub> =4.5V, I <sub>D</sub> =4A		34	48	mΩ
Forward Transconductance	g⊧s	V <sub>DS</sub> =5V,I <sub>D</sub> =6A		20	-	S
Dynamic Characteristics (Note4)			•		1 1	
Input Capacitance	Clss			1920		PF
Output Capacitance	Coss	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V, F=1.0MHz		155		PF
Reverse Transfer Capacitance	C <sub>rss</sub>	F=1.0MHz		116		PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t <sub>d(on)</sub>		-	8	-	nS
Turn-on Rise Time	t <sub>r</sub>	$V_{DS}$ =30V, R <sub>L</sub> =4.7 $\Omega$	-	5	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{GEN}$ =3 $\Omega$	-	29	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	6	-	nS
Total Gate Charge	Qg	V -20V/L -CA	-	50	-	nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =30V,I <sub>D</sub> =6A, V <sub>GS</sub> =10V	-	8	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> -10V	-	16	-	nC
Drain-Source Diode Characteristic	cs					
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =6A	-	-	1.2	V
Diode Forward Current (Note 2)	I <sub>S</sub>		-	-	7	Α
Reverse Recovery Time	t <sub>rr</sub>	TJ = 25°C, I <sub>F</sub> =7A	-	35	-	nS
Reverse Recovery Charge	Qrr	di/dt = 100A/µs <sup>(Note3)</sup>	-	43	-	nC
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

**2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.

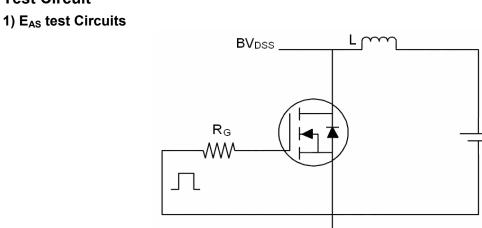
**3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.

4. Guaranteed by design, not subject to production

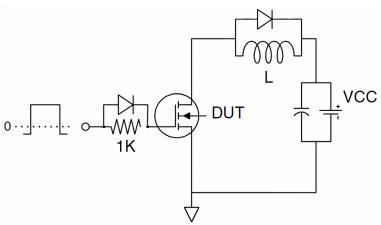


+ V<sub>DD</sub>

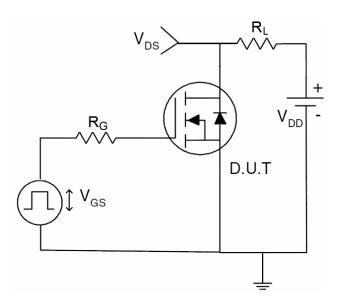
## Test Circuit



### 2) Gate charge test Circuit



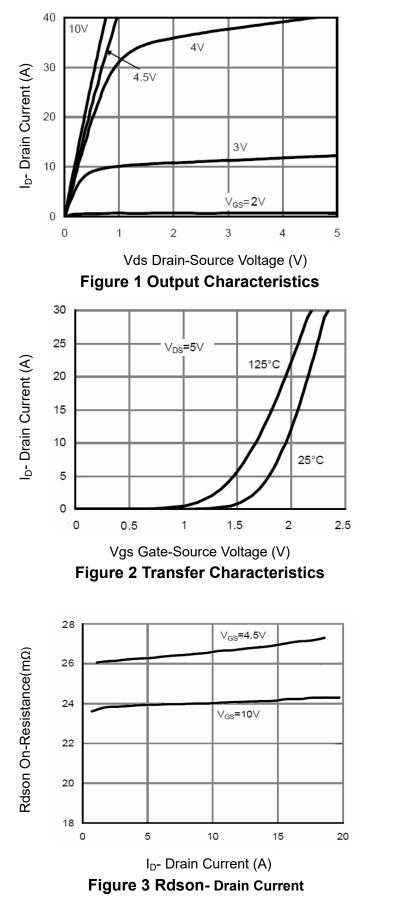
### 3) Switch Time Test Circuit





## DMNH6042SSDQ Dual N-Channel Enhancement Mode MOSFET

## **Typical Electrical and Thermal Characteristics (Curves)**



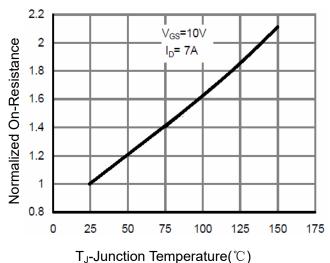


Figure 4 Rdson-JunctionTemperature

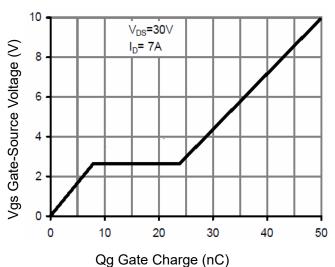


Figure 5 Gate Charge

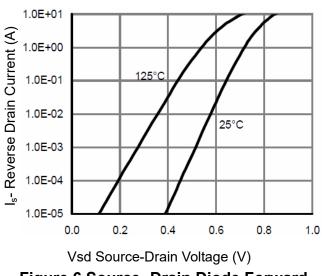
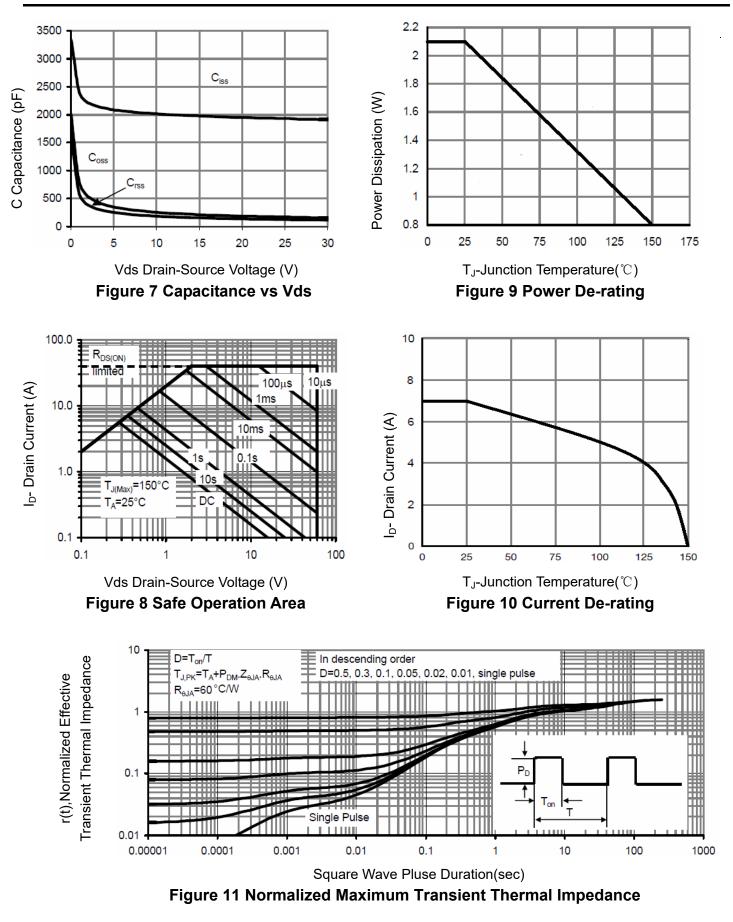


Figure 6 Source- Drain Diode Forward



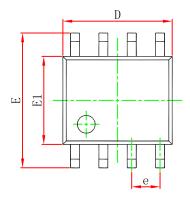
# DMNH6042SSDQ

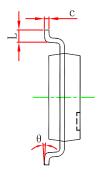
Dual N-Channel Enhancement Mode MOSFET

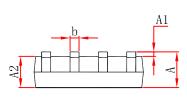




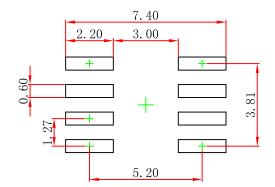
## SOP-8 Package Outline Dimensions







Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
А	1.350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
с	0.170	0.250	0.007	0.010	
D	4.800	5.000	0.189	0.197	
e	1.270 (BSC)		0.050 (BSC)		
E	5.800	6.200	0.228	0.244	
E1	3.800	4.000	0.150	0.157	
L	0.400	1.270	0.016	0.050	
θ	0 °	8°	0 °	8°	



Note: 1.Controlling dimension:in millimeters.

2.General tolerance:± 0.05mm.
 3.The pad layout is for reference purposes only.



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